Characterization of a Metamaterial-Enabled Waveguide Diplexer for Ka-Band Satellite Communication Systems

Robin F. Bonny^{1,2}, Mehri Ziaee Bideskan², Romain Fleury¹, Maliheh Khatibi Moghaddam², Mostafa Khosrownejad²

1: Laboratory of Wave Engineering, EPFL, Lausanne, Switzerland (robin.bonny@alumni.epfl.ch)
2: MinWave Technologies SA, Lausanne, Switzerland (m.khatibi@minwave.ch)

Abstract

We present a novel **miniaturized metamateri**al-enabled diplexer, together with measurement methodologies to characterize noncontiguous channels, within a waveguide structure. The studied diplexer efficiently separates receive (17.3 – 20.2 GHz) and transmit (27 – 31 GHz) Ka-band satellite communication channels utilizing a design approach that integrates **lo**cally resonant metamaterials (LRMs) and an evanescent mode junction. This integration allows for high rejection and low loss in an ultrasmall volume, effectively showcasing the capabilities of the diplexer. We precisely measure the passband and stopband of both the receive and transmit channels and compare the results with simulations.

–		
Parameter	RX passband	TX passband
Peak amplitude	-0.26 dB	-0.32 dB
Peak frequency	18.53 GHz	29.01 GHz
1 dB bandwidth	3.83 GHz	4.47 GHz
Lower freq. bound	17.19 GHz	27.45 GHz
Upper freq. bound	21.02 GHz	31.92 GHz
Typical insertion loss	0.64 dB	0.58 dB
Rejection	68.48 dB	67.91 dB

Diplexer Overview





FPF

RX/TX isolation 66.34 dB 64.61 dB

Properties of the measured diplexer



Fabricated diplexer prototype

Metamaterial Filters

- (a) Locally resonant metamaterials consist of **electrically small resonators** placed with sub- λ separations
- (b) A standard waveguide with Z_0 , k, f_c is used as a host
- (c) Scattering of incident fields induce an opposing phase shift and lead to the formation of a **hybridization bandgap (HBG)** in a waveguide below cutoff [1], [2]

(d) Simplified structure as a 1D periodic array



LRM in free space



Three major measurement challenges were addressed: **multi-port networks** (measuring a three-port device in a two-port measurement setup), **non-standard flanges** (adapting proprietary waveguide dimensions to standardized values), and **asymmetric networks** (different waveguide dimensions for different ports).

De-Embedding & Unterminating

- To isolate the DUT, the contribution of the test structure must be de-embedded [3]
- The *S*-parameters of the test structure can be determined via a **2x-thru measurement** [4]



De-embedding measurement with DUT



Frequency Fusion

- Using multiple waveguide standards requires frequency fusion techniques
- The embedding structure must be properly characterized for each employed waveguide
- Continuity of measurements indicate proper calibration
- Overlapping regions are combined via geometric means across measurements



Port Augmentation

Methods & Techniques

- Integrating a three-port device into a two-port measurement setup requires proper termination
- Appropriate techniques include impedance renormalization [5] and wave identification [6]
- The diplexer can be simplified by taking advantage of the port isolation





Concept of locally resonant metamaterial waveguides (LRMWs), reproduced from [1]



Schematic representation of an LRM waveguide host

Further Reading

This work was developed on the basis of a Master's thesis at École Polytechnique Fédérale



Unterminating with 2x-thru measurement

Waveguide operating frequency ranges



Measurements







R. F. Bonny "RF Measurements of Unconventional Miniaturised Filters and Diplexers" https://infoscience.epfl.ch/record/306796



Comparison between processed measurements and simulation results

References

[1] M. K. Moghaddam and R. Fleury, "Subwavelength Meta-Waveguide Filters and Meta-Ports," Physical Review Applied, 2021. DOI: 10.1103/PhysRevApplied.16.044010.

[2] M. K. Moghaddam and R. Fleury, "Slow light engineering in resonant photonic crystal line-defect waveguides," 2019. DOI: 10.1364/0E.27.026229.

[3] R. Bauer and P. Penfield, "De-Embedding and Unterminating," 1974. DOI: 10.1109/TMTT.1974.1128212.

[4] H. Barnes and J. Moreira, "Verifying the accuracy of 2x-Thru de-embedding for unsymmetrical test fixtures," 2017. DOI: 10.1109/EPEPS.2017.8329760.

[5] J. Tippet and R. Speciale, "A Rigorous Technique for Measuring the Scattering Matrix of a Multiport Device with a 2-Port Network Analyzer," 1982. DOI: 10.1109/TMTT. 1982. 1131118.

[6] I. Rolfes and B. Schiek, "Multiport method for the measurement of the scattering parameters of N-ports," 2005. DOI: 10.1109/TMTT. 2005. 848823.